

Notice of References Cited	Application/Control No. 09/807,959	Applicant(s)/Patent Under Reexamination BARTON ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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*	N	EP 0854620 A2	07-1998	EP	Nakamura, Jin	H04L 27/26
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NON-PATENT DOCUMENTS

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